

July 2007

FDFS2P753AZ

Integrated P-Channel PowerTrench® MOSFET and Schottky Diode -30V, -3A, 115m Ω

Features

- Max $r_{DS(on)}$ = 115m Ω at V_{GS} = -10V, I_D = -3.0A
- Max $r_{DS(on)} = 180 \text{m}\Omega$ at $V_{GS} = -4.5 \text{V}$, $I_D = -1.5 \text{A}$
- V_F < 0.45V @ 2A

V_F < 0.28V @ 100mA

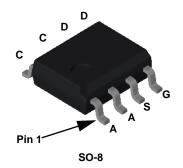
- Schottky and MOSFET incorporated into single power surface mount SO-8 package
- Electrically independent Schottky and MOSFET pinout for design flexibility
- RoHS Compliant

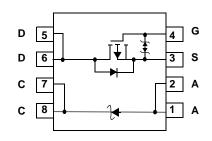
General Description

The FDFS2P753AZ offers a single package solution for DC/DC conversion. It combines an excellent Fairchild's PowerTrench MOSFET with a Schottky diode in an SO-8 package. The MOSFET features a low on-state resistance and an optimized gate charge to achieve fast switching. The independently connected Schottky diode has a low forward voltage drop to minimize power loss. This device is an Ideal DC-DC solution for up to 3A peak load current.

Applications

■ DC - DC Conversion





MOSFET Maximum Ratings T_A = 25°C unless otherwise noted

Symbol	Parameter	Ratings	Units		
V_{DS}	Drain to Source Voltage			-30	V
V_{GS}	Gate to Source Voltage			±25	V
I _D	Drain Current -Continuous		(Note 1a)	-3	۸
	-Pulsed			-16	_ A
D	Power Dissipation	$T_C = 25^{\circ}C$		3.1	W
P_{D}	Power Dissipation	T _A = 25°C	(Note 1a)	1.6	VV
E _{AS}	Single Pulse Avalanche Energy		(Note 2)	6	mJ
V_{RRM}	Schottky Repetitive Peak Reverse Voltage			30	V
Io	Schottky Average Forward Current			2	Α
T _J , T _{STG}	Operating and Storage Junction Temperature	Range		-55 to +150	°C

Thermal Characteristics

I	$R_{ heta JC}$	Thermal Resistance, Junction to Case	(Note 1)	40	°C/W
I	R _{e.IA}	Thermal Resistance, Junction to Ambient	(Note 1a)	78	C/VV

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDFS2P753AZ	FDFS2P753AZ	SO-8	330mm	12mm	2500units

Electrical Characteristics $T_J = 25^{\circ}\text{C}$ unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Chara	acteristics					
BV _{DSS}	Drain to Source Breakdown Voltage	$I_D = -250 \mu A, V_{GS} = 0 V$	-30			V
$\frac{\Delta BV_{DSS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	I_D = -250 μ A, referenced to 25°C		-21		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = -24V$, $V_{GS} = 0V$ $T_{J} = 125$ °C			-1 -100	μА
I _{GSS}	Gate to Source Leakage Current	$V_{GS} = \pm 25V$, $V_{DS} = 0V$			±10	μΑ

On Characteristics

V _{GS(th)}	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_D = -250 \mu A$	-1.0	-2.1	-3.0	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	$I_D = -250\mu\text{A}$, referenced to 25°C		5		mV/°C
	Static Drain to Source On Resistance	$V_{GS} = -10V, I_D = -3.0A$		69	115	
r _{DS(on)}		$V_{GS} = -4.5V, I_D = -1.5A$		115	180	mΩ
		$V_{GS} = -10V, I_D = -3.0A, T_J = 125$ °C		97	162	
9 _{FS}	Forward Transconductance	$V_{DD} = -5V, I_D = -3.0A$		6		S

Dynamic Characteristics

C _{iss}	Input Capacitance	\\ 15\\\\\ 0\\		330	455	pF
C _{oss}	Output Capacitance	$V_{DS} = -15V, V_{GS} = 0V,$ f = 1MHz		60	110	pF
C _{rss}	Reverse Transfer Capacitance			55	100	pF
R_g	Gate Resistance	f = 1MHz		18		Ω

Switching Characteristics

t _{d(on)}	Turn-On Delay Time	.,	6	12	ns
t _r	Rise Time	$V_{DD} = -15V, I_{D} = -3.0A,$ $V_{GS} = -10V, R_{GEN} = 6\Omega$	4	10	ns
t _{d(off)}	Turn-Off Delay Time	V _{GS} = -10V, R _{GEN} = 012	19	34	ns
t _f	Fall Time		15	27	ns
Q_g	Total Gate Charge	V _{GS} = 0V to -10V	7.9	11.0	nC
Qg	Total Gate Charge	$V_{GS} = 0V \text{ to } -4.5V$ $V_{DD} = -15V,$ $I_{D} = -3.0A$	4.1	5.7	nC
Q _{gs}	Gate to Source Charge	I _D = -3.0A	1.3		nC
Q _{gd}	Gate to Drain "Miller" Charge		2.0		nC

Drain-Source Diode Characteristics

V_{SD}	Source to Drain Diode Forward Voltage	$V_{GS} = 0V, I_{S} = -2.0A$ (Note 3)		-0.9	-1.2	V
t _{rr}	Reverse Recovery Time	- I _F = -3.0A, di/dt = 100A/μs		20	30	ns
Q_{rr}	Reverse Recovery Charge	I _F = -3.0A, α/αι = 100A/μS		14	21	nC

Schottky Diode Characteristics

V_R	Reverse Breakdown Voltage	$I_R = 1mA$		30			V
	I _R Reverse Leakage	\/ - 10\/	$T_J = 25^{\circ}C$		39	250	μΑ
'R		V _R = 10V	T _J = 125°C		18		mA
	Forward Voltage	I _F = 100mA	$T_J = 25^{\circ}C$		225	280	- mV
\/			T _J = 125°C		140		
V _F		I _F = 2A	$T_J = 25^{\circ}C$		364	450	
			T _J = 125°C		290		

NOTES:

 $1.R_{0,1A}$ is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. $R_{0,1C}$ is guaranteed by design while $R_{0,1C}$ is determined by the user's board design.



a. 78°C/W when mounted on a 0.5 in² pad of 2 oz copper.



b. 135°C/W when mounted on a minimum pad of 2 oz copper.

- 2. Starting T $_{J}$ = 25°C, L $\,$ = 3 mH, I $_{AS}$ = -2A, V $_{DD}$ = -27V, V $_{GS}$ = -10V.
- 3. Pulse Test: Pulse Width < 300μs, Duty cycle < 2.0%.

Typical Characteristics T_J = 25°C unless otherwise noted

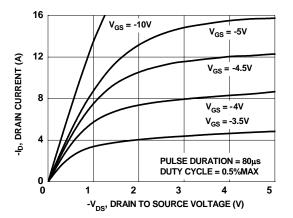


Figure 1. On-Region Characteristics

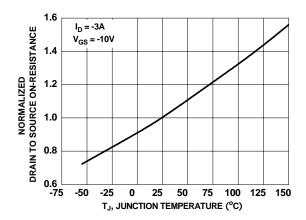


Figure 3. Normalized On-Resistance vs Junction Temperature

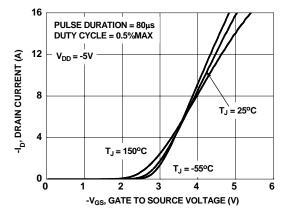


Figure 5. Transfer Characteristics

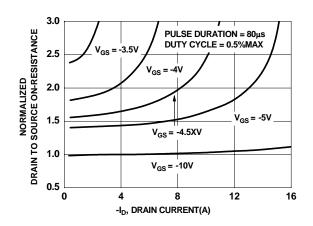


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

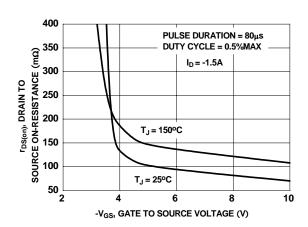


Figure 4. On-Resistance vs Gate to Source Voltage

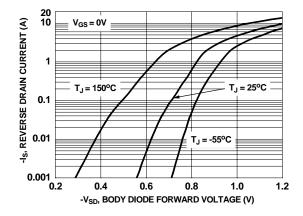


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

Typical Characteristics $T_J = 25^{\circ}C$ unless otherwise noted

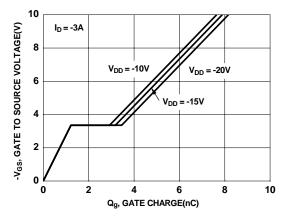


Figure 7. Gate Charge Characteristics

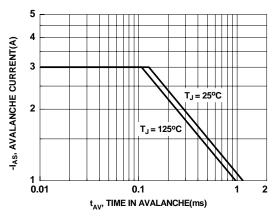


Figure 9. Unclamped Inductive Switching Capability

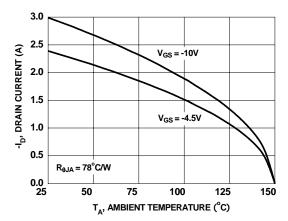


Figure 11. Maximum Continuous Drain Current vs Ambient Temperature

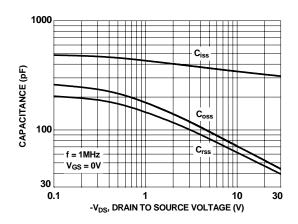


Figure 8. Capacitance vs Drain to Source Voltage

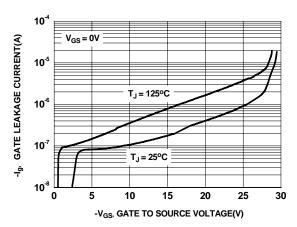


Figure 10. Gate Leakage Current vs Gate to Source Volatge

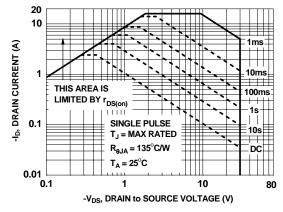
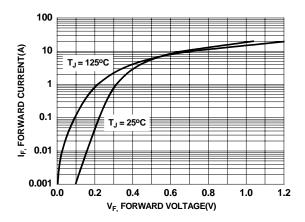


Figure 12. Forward Bias Safe Operating Area

Typical Characteristics T_J = 25°C unless otherwise noted



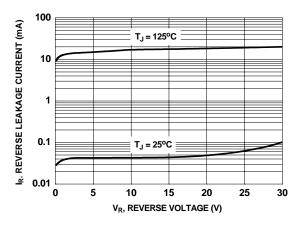


Figure 13. Schottky Diode Forward Voltage

Figure 14. Schottky Diode Reverse Current

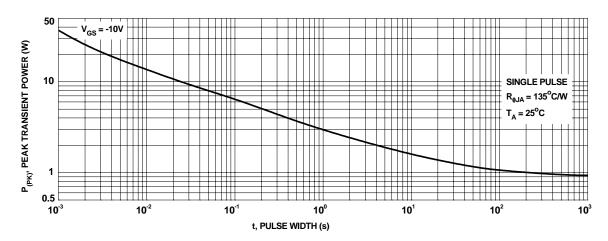


Figure 15. Single Pulse Maximum Power Dissipation

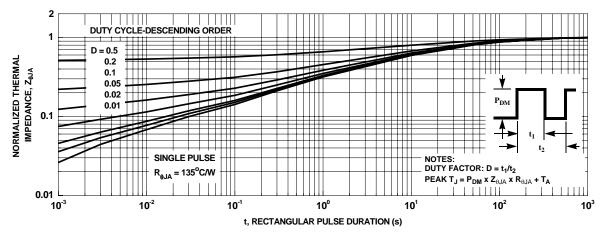


Figure 16. Transient Thermal Response Curve





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